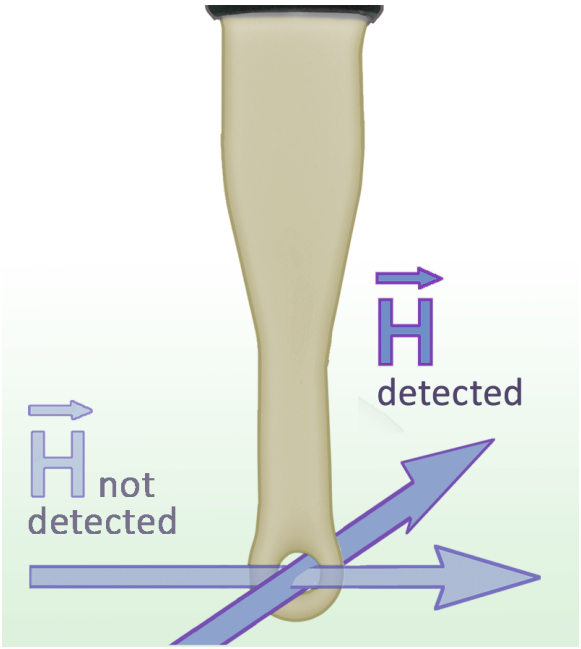
SX-R 3-1

H-Field Probe 1 GHz up to 10 GHz



Short description

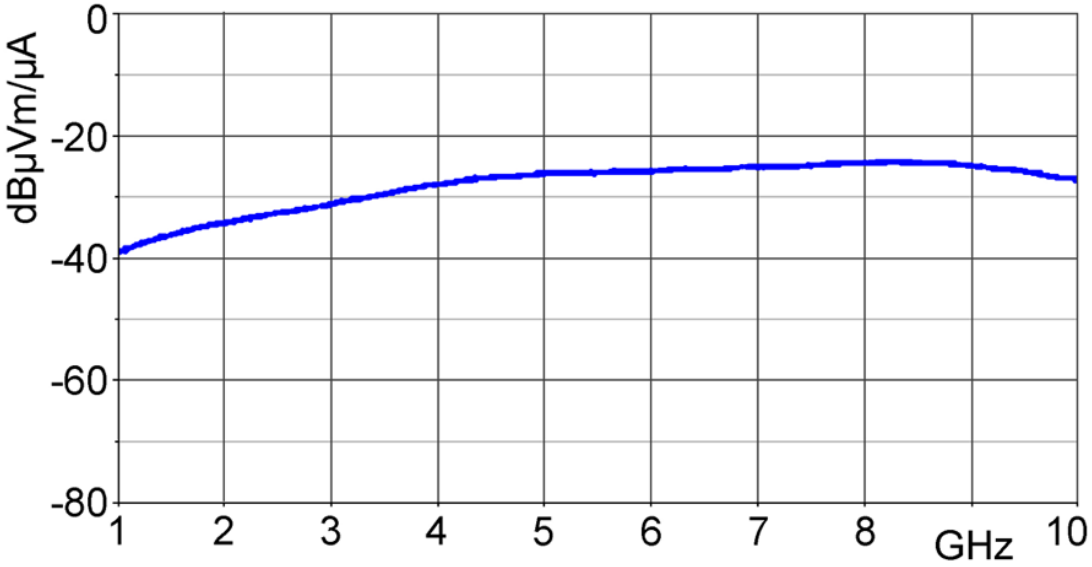
With its small probe head, the SX-R 3-1 can detect very high resolution RF-magnetic fields and can, therefore, identify even the smallest components as interference sources. Furthermore, the small probe head is designed to allow for measurements at less accessible areas, e.g. near IC pins.

The SX-R 3-1 is a passive near-field probe. The probe head is very small and therefore suitable for detection of magnetic-field distribution, e.g. at ICs. Because of its compact design, the SX-R 3-1 can be used at hard to reach spots ,e.g. between components. It has a current attenuating sheath and its upper side is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input.

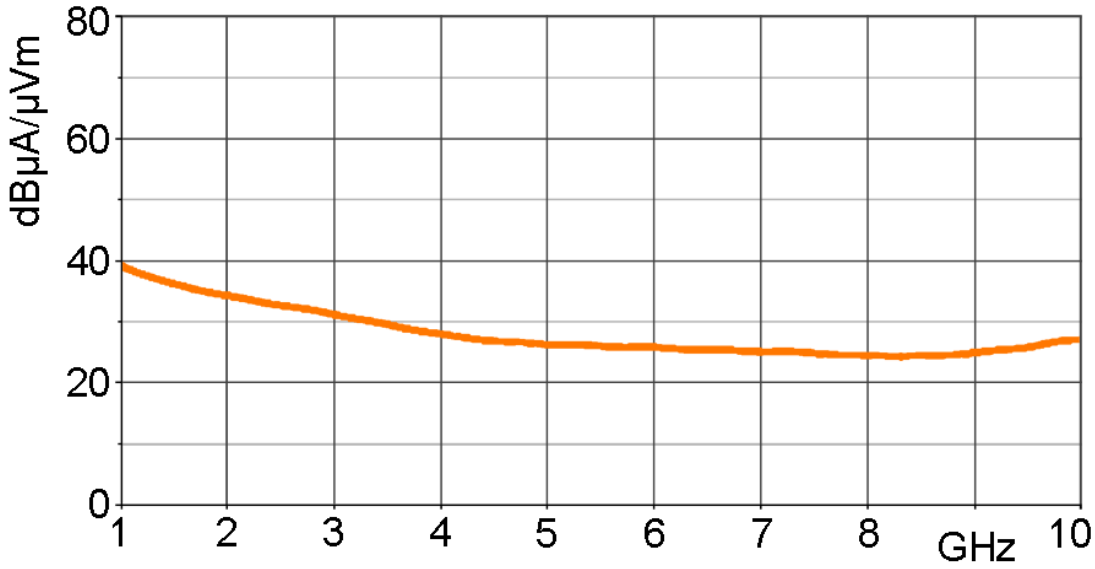
Technical parameters

Frequency range	1 GHz ... 10 GHz
Resolution	≈ 1 mm
Probe head dimensions	Ø ≈ 3 mm
Connector - output	SMA, female, jack

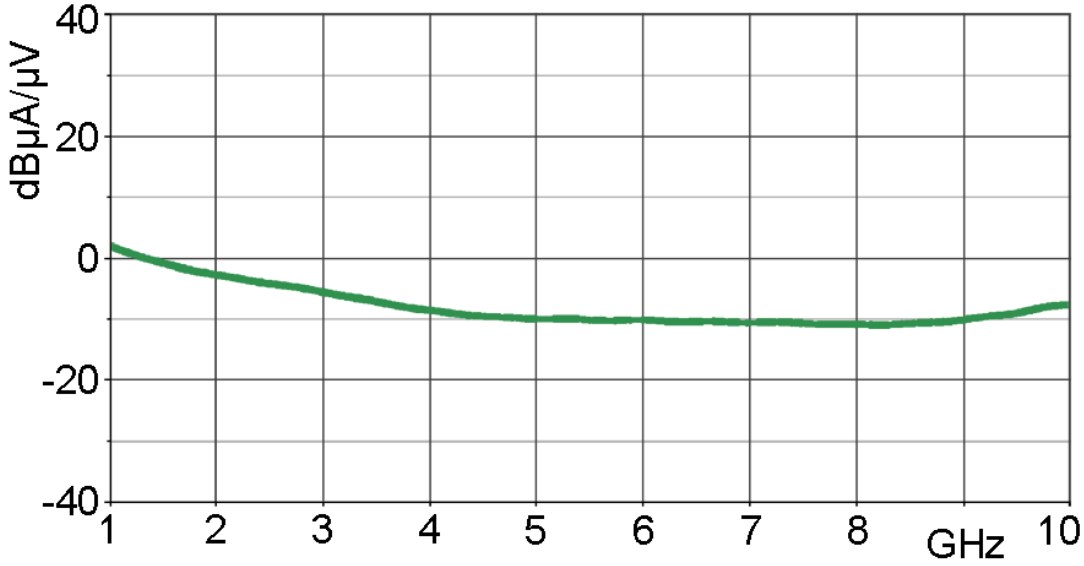
Frequency response [dBµV] / [dBµA/m]



H-field correction curve [dBµA/m] / [dBµV]



Current correction curve [dBµA] / [dBµV]



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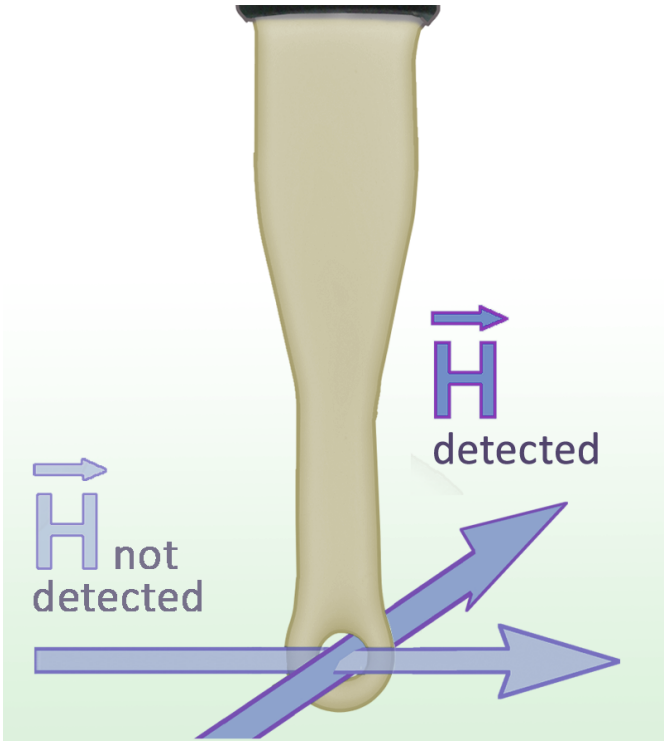
Measuring principles



Probe head